AMD Xilinx - XCV100-4PQ240C Datasheet

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Understanding Embedded - FPGAs (Field Programmable Gate Array)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications,

Details	
Product Status	Obsolete
Number of LABs/CLBs	600
Number of Logic Elements/Cells	2700
Total RAM Bits	40960
Number of I/O	166
Number of Gates	108904
Voltage - Supply	2.375V ~ 2.625V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 85°C (TJ)
Package / Case	240-BFQFP
Supplier Device Package	240-PQFP (32x32)
Purchase URL	https://www.e-xfl.com/product-detail/xilinx/xcv100-4pq240c

Virtex Architecture

Virtex devices feature a flexible, regular architecture that comprises an array of configurable logic blocks (CLBs) surrounded by programmable input/output blocks (IOBs), all interconnected by a rich hierarchy of fast, versatile routing resources. The abundance of routing resources permits the Virtex family to accommodate even the largest and most complex designs.

Virtex FPGAs are SRAM-based, and are customized by loading configuration data into internal memory cells. In some modes, the FPGA reads its own configuration data from an external PROM (master serial mode). Otherwise, the configuration data is written into the FPGA (SelectMAP™, slave serial, and JTAG modes).

The standard Xilinx Foundation™ and Alliance Series™ Development systems deliver complete design support for Virtex, covering every aspect from behavioral and schematic entry, through simulation, automatic design translation and implementation, to the creation, downloading, and readback of a configuration bit stream.

Higher Performance

Virtex devices provide better performance than previous generations of FPGA. Designs can achieve synchronous system clock rates up to 200 MHz including I/O. Virtex inputs and outputs comply fully with PCI specifications, and interfaces can be implemented that operate at 33 MHz or 66 MHz. Additionally, Virtex supports the hot-swapping requirements of Compact PCI.

Xilinx thoroughly benchmarked the Virtex family. While performance is design-dependent, many designs operated internally at speeds in excess of 100 MHz and can achieve 200 MHz. Table 2 shows performance data for representative circuits, using worst-case timing parameters.

Table 2: **Performance for Common Circuit Functions**

Function	Bits	Virtex -6
Register-to-Register		
Adder	16 64	5.0 ns 7.2 ns
Pipelined Multiplier	8 x 8 16 x 16	5.1 ns 6.0 ns
Address Decoder	16 64	4.4 ns 6.4 ns
16:1 Multiplexer		5.4 ns
Parity Tree	9 18 36	4.1 ns 5.0 ns 6.9 ns
Chip-to-Chip		
HSTL Class IV		200 MHz
LVTTL,16mA, fast slew		180 MHz

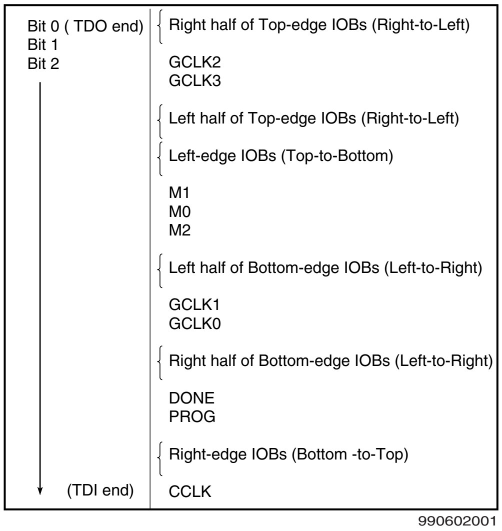

Figure 11: **Boundary Scan Bit Sequence**

Table 5: **Boundary Scan Instructions**

Boundary-Scan Command	Binary Code(4:0)	Description
EXTEST	00000	Enables boundary-scan EXTEST operation
SAMPLE/PRELOAD	00001	Enables boundary-scan SAMPLE/PRELOAD operation
USER 1	00010	Access user-defined register 1
USER 2	00011	Access user-defined register 2
CFG_OUT	00100	Access the configuration bus for read operations.
CFG_IN	00101	Access the configuration bus for write operations.
INTEST	00111	Enables boundary-scan INTEST operation
USERCODE	01000	Enables shifting out USER code
IDCODE	01001	Enables shifting out of ID Code
HIGHZ	01010	3-states output pins while enabling the Bypass Register
JSTART	01100	Clock the start-up sequence when StartupClk is TCK
BYPASS	11111	Enables BYPASS
RESERVED	All other codes	Xilinx reserved instructions

Identification Registers

The IDCODE register is supported. By using the IDCODE, the device connected to the JTAG port can be determined.

The IDCODE register has the following binary format:

vvvv:ffff:fffa:aaaa:aaaa:cccc:cccc:ccc1

where

v = the die version number

f = the family code (03h for Virtex family)

a = the number of CLB rows (ranges from 010h for XCV50 to 040h for XCV1000)

c = the company code (49h for Xilinx)

The USERCODE register is supported. By using the USERCODE, a user-programmable identification code can be loaded and shifted out for examination. The identification code is embedded in the bitstream during bitstream generation and is valid only after configuration.

Table 6: **IDCODEs Assigned to Virtex FPGAs**

FPGA	IDCODE
XCV50	v0610093h
XCV100	v0614093h
XCV150	v0618093h
XCV200	v061C093h
XCV300	v0620093h
XCV400	v0628093h
XCV600	v0630093h
XCV800	v0638093h
XCV1000	v0640093h

Including Boundary Scan in a Design

Since the boundary scan pins are dedicated, no special element needs to be added to the design unless an internal data register (USER1 or USER2) is desired.

If an internal data register is used, insert the boundary scan symbol and connect the necessary pins as appropriate.

Development System

Virtex FPGAs are supported by the Xilinx Foundation and Alliance CAE tools. The basic methodology for Virtex design consists of three interrelated steps: design entry, implementation, and verification. Industry-standard tools are used for design entry and simulation (for example, Synopsys FPGA Express), while Xilinx provides proprietary architecture-specific tools for implementation.

The Xilinx development system is integrated under the Xilinx Design Manager (XDM™) software, providing design-

Configuration

Virtex devices are configured by loading configuration data into the internal configuration memory. Some of the pins used for this are dedicated configuration pins, while others can be re-used as general purpose inputs and outputs once configuration is complete.

The following are dedicated pins:

- Mode pins (M2, M1, M0)
- Configuration clock pin (CCLK)
- $\overline{\text{PROGRAM}}$ pin
- DONE pin
- Boundary-scan pins (TDI, TDO, TMS, TCK)

Depending on the configuration mode chosen, CCLK can be an output generated by the FPGA, or it can be generated externally and provided to the FPGA as an input. The $\overline{\text{PROGRAM}}$ pin must be pulled High prior to reconfiguration.

Note that some configuration pins can act as outputs. For correct operation, these pins can require a V_{CCO} of 3.3 V to permit LVTTL operation. All the pins affected are in banks 2 or 3. The configuration pins needed for SelectMap (CS, Write) are located in bank 1.

After Virtex devices are configured, unused IOBs function as 3-state OBUFTs with weak pull downs. For a more detailed description than that given below, see the XAPP138, Virtex Configuration and Readback.

Configuration Modes

Virtex supports the following four configuration modes.

- Slave-serial mode
- Master-serial mode
- SelectMAP mode
- Boundary-scan mode

The Configuration mode pins (M2, M1, M0) select among these configuration modes with the option in each case of having the IOB pins either pulled up or left floating prior to configuration. The selection codes are listed in Table 7.

Configuration through the boundary-scan port is always available, independent of the mode selection. Selecting the boundary-scan mode simply turns off the other modes. The three mode pins have internal pull-up resistors, and default to a logic High if left unconnected. However, it is recommended to drive the configuration mode pins externally.

Table 7: **Configuration Codes**

Configuration Mode	M2	M1	M0	CCLK Direction	Data Width	Serial D_{out}	Configuration Pull-ups
Master-serial mode	0	0	0	Out	1	Yes	No
Boundary-scan mode	1	0	1	N/A	1	No	No
SelectMAP mode	1	1	0	In	8	No	No
Slave-serial mode	1	1	1	In	1	Yes	No
Master-serial mode	1	0	0	Out	1	Yes	Yes
Boundary-scan mode	0	0	1	N/A	1	No	Yes
SelectMAP mode	0	1	0	In	8	No	Yes
Slave-serial mode	0	1	1	In	1	Yes	Yes

Slave-Serial Mode

In slave-serial mode, the FPGA receives configuration data in bit-serial form from a serial PROM or other source of serial configuration data. The serial bitstream must be setup at the DIN input pin a short time before each rising edge of an externally generated CCLK.

For more information on serial PROMs, see the PROM data sheet at:
http://www.xilinx.com/bvdocs/publications/ds026.pdf.

Multiple FPGAs can be daisy-chained for configuration from a single source. After a particular FPGA has been configured, the data for the next device is routed to the DOUT pin. The data on the DOUT pin changes on the rising edge of CCLK.

The change of DOUT on the rising edge of CCLK differs from previous families, but does not cause a problem for mixed configuration chains. This change was made to improve serial configuration rates for Virtex-only chains.

Figure 12 shows a full master/slave system. A Virtex device in slave-serial mode should be connected as shown in the third device from the left.

Slave-serial mode is selected by applying <111> or <011> to the mode pins (M2, M1, M0). A weak pull-up on the mode pins makes slave-serial the default mode if the pins are left unconnected. However, it is recommended to drive the configuration mode pins externally. Figure 13 shows slave-serial mode programming switching characteristics.

Table 8 provides more detail about the characteristics shown in Figure 13. Configuration must be delayed until the $\overline{\text{INIT}}$ pins of all daisy-chained FPGAs are High.

Master-Serial Mode

In master-serial mode, the CCLK output of the FPGA drives a Xilinx Serial PROM that feeds bit-serial data to the DIN input. The FPGA accepts this data on each rising CCLK edge. After the FPGA has been loaded, the data for the next device in a daisy-chain is presented on the DOUT pin after the rising CCLK edge.

The interface is identical to slave-serial except that an internal oscillator is used to generate the configuration clock (CCLK). A wide range of frequencies can be selected for CCLK which always starts at a slow default frequency. Configuration bits then switch CCLK to a higher frequency for the remainder of the configuration. Switching to a lower frequency is prohibited.

The CCLK frequency is set using the ConfigRate option in the bitstream generation software. The maximum CCLK frequency that can be selected is 60 MHz. When selecting a CCLK frequency, ensure that the serial PROM and any daisy-chained FPGAs are fast enough to support the clock rate.

On power-up, the CCLK frequency is 2.5 MHz. This frequency is used until the ConfigRate bits have been loaded when the frequency changes to the selected ConfigRate. Unless a different frequency is specified in the design, the default ConfigRate is 4 MHz.

Figure 12 shows a full master/slave system. In this system, the left-most device operates in master-serial mode. The remaining devices operate in slave-serial mode. The SPROM $\overline{\text{RESET}}$ pin is driven by $\overline{\text{INIT}}$, and the $\overline{\text{CE}}$ input is driven by DONE. There is the potential for contention on the DONE pin, depending on the start-up sequence options chosen.

Figure 14 shows the timing of master-serial configuration. Master-serial mode is selected by a <000> or <100> on the mode pins (M2, M1, M0). Table 8 shows the timing information for Figure 14.

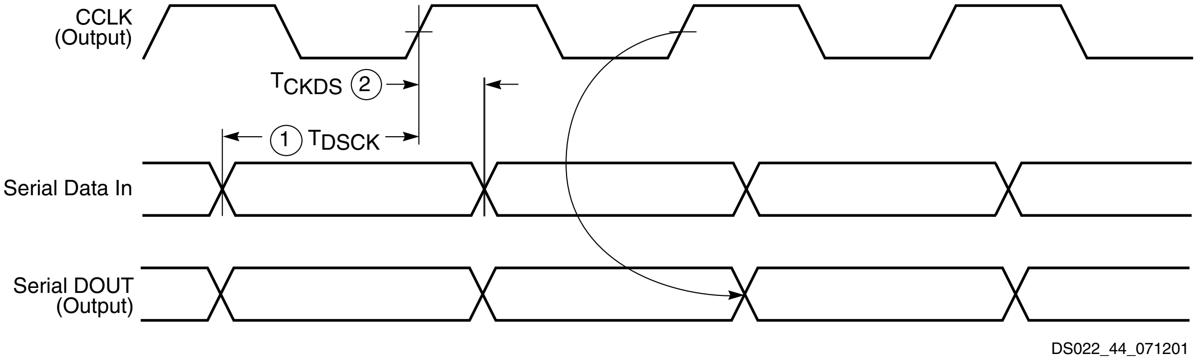

Figure 14: **Master-Serial Mode Programming Switching Characteristics**

At power-up, V_{CC} must rise from 1.0 V to V_{CC} min in less than 50 ms, otherwise delay configuration by pulling $\overline{\text{PROGRAM}}$ Low until V_{CC} is valid.

The sequence of operations necessary to configure a Virtex FPGA serially appears in Figure 15.

SelectMAP Mode

The SelectMAP mode is the fastest configuration option. Byte-wide data is written into the FPGA with a BUSY flag controlling the flow of data.

An external data source provides a byte stream, CCLK, a Chip Select ($\overline{\text{CS}}$) signal and a Write signal ($\overline{\text{WRITE}}$). If BUSY is asserted (High) by the FPGA, the data must be held until BUSY goes Low.

Data can also be read using the SelectMAP mode. If $\overline{\text{WRITE}}$ is not asserted, configuration data is read out of the FPGA as part of a readback operation.

In the SelectMAP mode, multiple Virtex devices can be chained in parallel. DATA pins (D7:D0), CCLK, $\overline{\text{WRITE}}$, $\overline{\text{BUSY}}$, $\overline{\text{PROGRAM}}$, DONE, and $\overline{\text{INIT}}$ can be connected in parallel between all the FPGAs. Note that the data is organized with the MSB of each byte on pin DO and the LSB of each byte on D7. The $\overline{\text{CS}}$ pins are kept separate, insuring that each FPGA can be selected individually. $\overline{\text{WRITE}}$ should be Low before loading the first bitstream and returned High after the last device has been programmed. Use $\overline{\text{CS}}$ to select the appropriate FPGA for loading the bitstream and sending the configuration data. at the end of the bitstream, deselect the loaded device and select the next target FPGA by setting its $\overline{\text{CS}}$ pin High. A free-running oscillator or other externally generated signal can be used for CCLK. The $\overline{\text{BUSY}}$ signal can be ignored for frequencies below 50 MHz. For details about frequencies above 50 MHz, see XAPP138, Virtex Configuration and Readback. Once all the devices have been programmed, the DONE pin goes High.

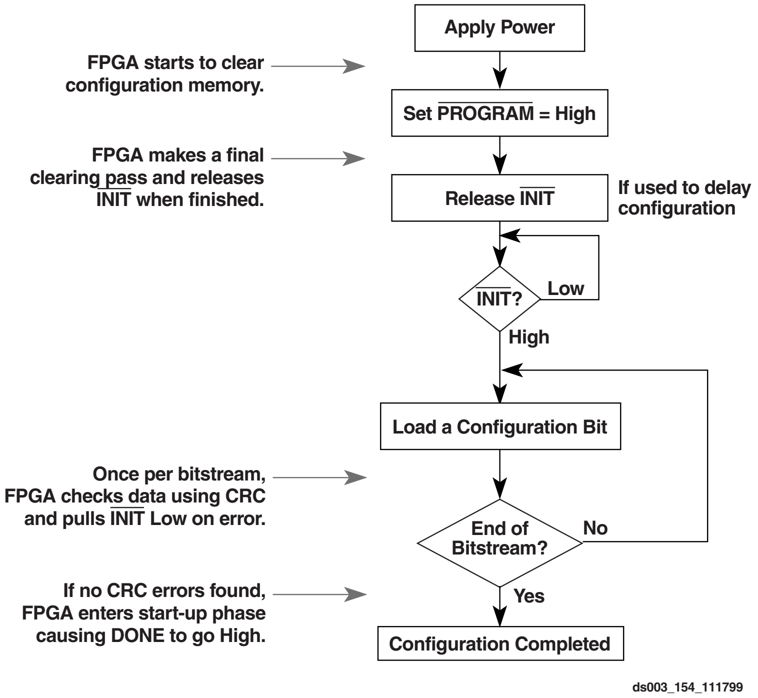

Figure 15: **Serial Configuration Flowchart**

After configuration, the pins of the SelectMAP port can be used as additional user I/O. Alternatively, the port can be retained to permit high-speed 8-bit readback.

Retention of the SelectMAP port is selectable on a design-by-design basis when the bitstream is generated. If retention is selected, PROHIBIT constraints are required to prevent the SelectMAP-port pins from being used as user I/O.

Multiple Virtex FPGAs can be configured using the SelectMAP mode, and be made to start-up simultaneously. To configure multiple devices in this way, wire the individual CCLK, Data, $\overline{\text{WRITE}}$, and BUSY pins of all the devices in parallel. The individual devices are loaded separately by asserting the $\overline{\text{CS}}$ pin of each device in turn and writing the appropriate data. see Table 9 for SelectMAP Write Timing Characteristics.

Table 9: **SelectMAP Write Timing Characteristics**

	Description		Symbol		Units
CCLK	D_{0-7} Setup/Hold	1/2	T_{SMDCC}/T_{SMCCD}	5.0 / 1.7	ns, min
	$\overline{\text{CS}}$ Setup/Hold	3/4	T_{SMCSCC}/T_{SMCCCS}	7.0 / 1.7	ns, min
	$\overline{\text{WRITE}}$ Setup/Hold	5/6	T_{SMCCW}/T_{SMWCC}	7.0 / 1.7	ns, min
	BUSY Propagation Delay	7	T_{SMCKBY}	12.0	ns, max
	Maximum Frequency		F_{CC}	66	MHz, max
	Maximum Frequency with no handshake		F_{CCNH}	50	MHz, max

Write

Write operations send packets of configuration data into the FPGA. The sequence of operations for a multi-cycle write operation is shown below. Note that a configuration packet can be split into many such sequences. The packet does not have to complete within one assertion of $\overline{\text{CS}}$, illustrated in Figure 16.

1. Assert $\overline{\text{WRITE}}$ and $\overline{\text{CS}}$ Low. Note that when $\overline{\text{CS}}$ is asserted on successive CCLKs, $\overline{\text{WRITE}}$ must remain either asserted or de-asserted. Otherwise an abort will be initiated, as described below.
2. Drive data onto D[7:0]. Note that to avoid contention, the data source should not be enabled while $\overline{\text{CS}}$ is Low and $\overline{\text{WRITE}}$ is High. Similarly, while $\overline{\text{WRITE}}$ is High, no more that one $\overline{\text{CS}}$ should be asserted.

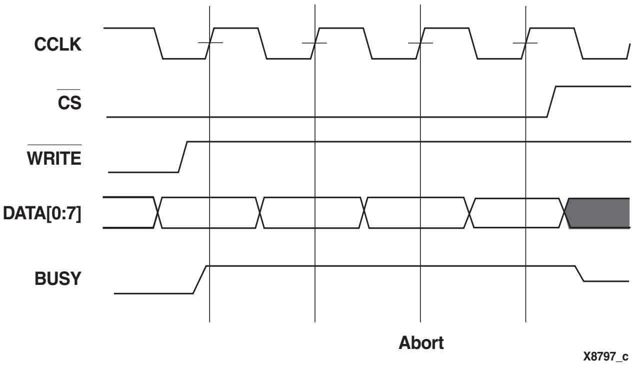

Figure 18: **SelectMAP Write Abort Waveforms**

Boundary-Scan Mode

In the boundary-scan mode, configuration is done through the IEEE 1149.1 Test Access Port. Note that the $\overline{\text{PROGRAM}}$ pin must be pulled High prior to reconfiguration. A Low on the $\overline{\text{PROGRAM}}$ pin resets the TAP controller and no JTAG operations can be performed.

Configuration through the TAP uses the CFG_IN instruction. This instruction allows data input on TDI to be converted into data packets for the internal configuration bus.

The following steps are required to configure the FPGA through the boundary-scan port (when using TCK as a start-up clock).

1. Load the CFG_IN instruction into the boundary-scan instruction register (IR)
2. Enter the Shift-DR (SDR) state
3. Shift a configuration bitstream into TDI
4. Return to Run-Test-Idle (RTI)
5. Load the JSTART instruction into IR
6. Enter the SDR state
7. Clock TCK through the startup sequence
8. Return to RTI

Configuration and readback via the TAP is always available. The boundary-scan mode is selected by a <101> or 001> on the mode pins (M2, M1, M0). For details on TAP characteristics, refer to XAPP139.

Configuration Sequence

The configuration of Virtex devices is a three-phase process. First, the configuration memory is cleared. Next, configuration data is loaded into the memory, and finally, the logic is activated by a start-up process.

Configuration is automatically initiated on power-up unless it is delayed by the user, as described below. The configuration process can also be initiated by asserting $\overline{\text{PROGRAM}}$.

The end of the memory-clearing phase is signalled by $\overline{\text{INIT}}$ going High, and the completion of the entire process is signalled by DONE going High.

The power-up timing of configuration signals is shown in Figure 19. The corresponding timing characteristics are listed in Table 10.

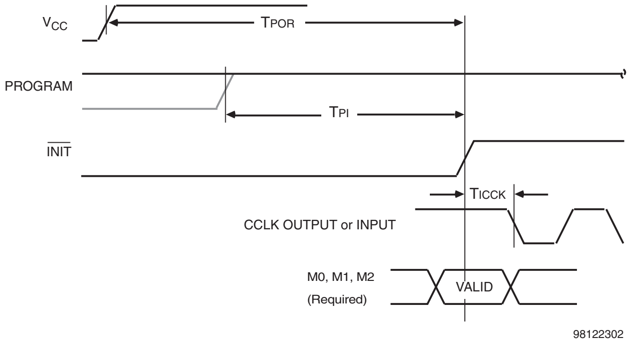

Figure 19: **Power-Up Timing Configuration Signals**

Table 10: **Power-up Timing Characteristics**

Description	Symbol	Value	Units
Power-on Reset	T_{POR}	2.0	ms, max
Program Latency	T_{PL}	100.0	µs, max
CCLK (output) Delay	T_{ICCK}	0.5	µs, min
		4.0	µs, max
Program Pulse Width	$T_{PROGRAM}$	300	ns, min

Delaying Configuration

$\overline{\text{INIT}}$ can be held Low using an open-drain driver. An open-drain is required since $\overline{\text{INIT}}$ is a bidirectional open-drain pin that is held Low by the FPGA while the configuration memory is being cleared. Extending the time that the pin is Low causes the configuration sequencer to wait. Thus, configuration is delayed by preventing entry into the phase where data is loaded.

Start-Up Sequence

The default Start-up sequence is that one CCLK cycle after DONE goes High, the global 3-state signal (GTS) is released. This permits device outputs to turn on as necessary.

One CCLK cycle later, the Global Set/Reset (GSR) and Global Write Enable (GWE) signals are released. This permits the internal storage elements to begin changing state in response to the logic and the user clock.

The relative timing of these events can be changed. In addition, the GTS, GSR, and GWE events can be made dependent on the DONE pins of multiple devices all going High, forcing the devices to start in synchronism. The sequence can also be paused at any stage until lock has been achieved on any or all DLLs.

Data Stream Format

Virtex devices are configured by sequentially loading frames of data. Table 11 lists the total number of bits required to configure each device. For more detailed information, see application note XAPP151 "Virtex Configuration Architecture Advanced Users Guide".

Table 11: **Virtex Bit-Stream Lengths**

Device	# of Configuration Bits
XCV50	559,200
XCV100	781,216
XCV150	1,040,096
XCV200	1,335,840
XCV300	1,751,808
XCV400	2,546,048
XCV600	3,607,968
XCV800	4,715,616
XCV1000	6,127,744

Readback

The configuration data stored in the Virtex configuration memory can be readback for verification. Along with the configuration data it is possible to readback the contents all flip-flops/latches, LUTRAMs, and block RAMs. This capability is used for real-time debugging.

For more detailed information, see Application Note XAPP138**:** *Virtex FPGA Series Configuration and Readback*, available online at www.xilinx.com.

Revision History

Date	Version	Revision
11/98	1.0	Initial Xilinx release.
01/99	1.2	Updated package drawings and specs.
02/99	1.3	Update of package drawings, updated specifications.
05/99	1.4	Addition of package drawings and specifications.
05/99	1.5	Replaced FG 676 & FG680 package drawings.
07/99	1.6	Changed Boundary Scan Information and changed Figure 11, Boundary Scan Bit Sequence. Updated IOB Input & Output delays. Added Capacitance info for different I/O Standards. Added 5 V tolerant information. Added DLL Parameters and waveforms and new Pin-to-pin Input and Output Parameter tables for Global Clock Input to Output and Setup and Hold. Changed Configuration Information including Figures 12, 14, 17 & 19. Added device-dependent listings for quiescent currents ICCINTQ and ICCOQ. Updated IOB Input and Output Delays based on default standard of LVTTL, 12 mA, Fast Slew Rate. Added IOB Input Switching Characteristics Standard Adjustments.
09/99	1.7	Speed grade update to preliminary status, Power-on specification and Clock-to-Out Minimums additions, "0" hold time listing explanation, quiescent current listing update, and Figure 6 ADDRA input label correction. Added T_{IJITCC} parameter, changed T_{OJIT} to T_{OPHASE}.
01/00	1.8	Update to speed.txt file 1.96. Corrections for CRs 111036,111137, 112697, 115479, 117153, 117154, and 117612. Modified notes for Recommended Operating Conditions (voltage and temperature). Changed Bank information for V_{CCO} in CS144 package on p.43.

Virtex Switching Characteristics

All devices are 100% functionally tested. Internal timing parameters are derived from measuring internal test patterns. Listed below are representative values. For more specific, more precise, and worst-case guaranteed data, use the values reported by the static timing analyzer (TRCE in the Xilinx Development System) and back-annotated to the simulation net list. All timing parameters assume worst-case operating conditions (supply voltage and junction temperature). Values apply to all Virtex devices unless otherwise noted.

IOB Input Switching Characteristics

Input delays associated with the pad are specified for LVTTL levels. For other standards, adjust the delays with the values shown in , page 6.

Description	Device	Symbol	Speed Grade				Units
			Min	-6	-5	-4	
Propagation Delays							
Pad to I output, no delay	All	T_{IOPI}	0.39	0.8	0.9	1.0	ns, max
Pad to I output, with delay	XCV50	T_{IOPID}	0.8	1.5	1.7	1.9	ns, max
	XCV100		0.8	1.5	1.7	1.9	ns, max
	XCV150		0.8	1.5	1.7	1.9	ns, max
	XCV200		0.8	1.5	1.7	1.9	ns, max
	XCV300		0.8	1.5	1.7	1.9	ns, max
	XCV400		0.9	1.8	2.0	2.3	ns, max
	XCV600		0.9	1.8	2.0	2.3	ns, max
	XCV800		1.1	2.1	2.4	2.7	ns, max
	XCV1000		1.1	2.1	2.4	2.7	ns, max
Pad to output IQ via transparent latch, no delay	All	T_{IOPLI}	0.8	1.6	1.8	2.0	ns, max
Pad to output IQ via transparent latch, with delay	XCV50	T_{IOPLID}	1.9	3.7	4.2	4.8	ns, max
	XCV100		1.9	3.7	4.2	4.8	ns, max
	XCV150		2.0	3.9	4.3	4.9	ns, max
	XCV200		2.0	4.0	4.4	5.1	ns, max
	XCV300		2.0	4.0	4.4	5.1	ns, max
	XCV400		2.1	4.1	4.6	5.3	ns, max
	XCV600		2.1	4.2	4.7	5.4	ns, max
	XCV800		2.2	4.4	4.9	5.6	ns, max
	XCV1000		2.3	4.5	5.1	5.8	ns, max
Sequential Delays							
Clock CLK	All						
Minimum Pulse Width, High		T_{CH}	0.8	1.5	1.7	2.0	ns, min
Minimum Pulse Width, Low		T_{CL}	0.8	1.5	1.7	2.0	ns, min
Clock CLK to output IQ		T_{IOCKIQ}	0.2	0.7	0.7	0.8	ns, max

Description	Device	Symbol	Speed Grade				Units
			Min	-6	-5	-4	
Setup and Hold Times with respect to Clock CLK at IOB input register[1]			**Setup Time / Hold Time**				
Pad, no delay	All	T_{IOPICK}/T_{IOICKP}	0.8 / 0	1.6 / 0	1.8 / 0	2.0 / 0	ns, min
Pad, with delay	XCV50	$T_{IOPICKD}/T_{IOICKPD}$	1.9 / 0	3.7 / 0	4.1 / 0	4.7 / 0	ns, min
	XCV100		1.9 / 0	3.7 / 0	4.1 / 0	4.7 / 0	ns, min
	XCV150		1.9 / 0	3.8 / 0	4.3 / 0	4.9 / 0	ns, min
	XCV200		2.0 / 0	3.9 / 0	4.4 / 0	5.0 / 0	ns, min
	XCV300		2.0 / 0	3.9 / 0	4.4 / 0	5.0 / 0	ns, min
	XCV400		2.1 / 0	4.1 / 0	4.6 / 0	5.3 / 0	ns, min
	XCV600		2.1 / 0	4.2 / 0	4.7 / 0	5.4 / 0	ns, min
	XCV800		2.2 / 0	4.4 / 0	4.9 / 0	5.6 / 0	ns, min
	XCV1000		2.3 / 0	4.5 / 0	5.0 / 0	5.8 / 0	ns, min
ICE input	All	$T_{IOICECK}/T_{IOCKICE}$	0.37/ 0	0.8 / 0	0.9 / 0	1.0 / 0	ns, max
Set/Reset Delays							
SR input (IFF, synchronous)	All	$T_{IOSRCKI}$	0.49	1.0	1.1	1.3	ns, max
SR input to IQ (asynchronous)	All	T_{IOSRIQ}	0.70	1.4	1.6	1.8	ns, max
GSR to output IQ	All	T_{GSRQ}	4.9	9.7	10.9	12.5	ns, max

Notes:

1. A Zero "0" Hold Time listing indicates no hold time or a negative hold time. Negative values cannot be guaranteed "best-case", but if a "0" is listed, there is no positive hold time.
2. Input timing for LVTTL is measured at 1.4 V. For other I/O standards, see Table 3.

Description	Symbol	Speed Grade				Units
		Min	-6	-5	-4	
Clock CLK to Pad delay with OBUFT enabled (non-3-state)	T_{IOCKP}	1.0	2.9	3.2	3.5	ns, max
Clock CLK to Pad high-impedance (synchronous)(1)	T_{IOCKHZ}	1.1	2.3	2.5	2.9	ns, max
Clock CLK to valid data on Pad delay, plus enable delay for OBUFT	T_{IOCKON}	1.5	3.4	3.7	4.1	ns, max
Setup and Hold Times before/after Clock CLK(2)		**Setup Time / Hold Time**				
O input	T_{IOOCK}/T_{IOCKO}	0.51 / 0	1.1 / 0	1.2 / 0	1.3 / 0	ns, min
OCE input	$T_{IOOCECK}/T_{IOCKOCE}$	0.37 / 0	0.8 / 0	0.9 / 0	1.0 / 0	ns, min
SR input (OFF)	$T_{IOSRCKO}/T_{IOCKOSR}$	0.52 / 0	1.1 / 0	1.2 / 0	1.4 / 0	ns, min
3-State Setup Times, T input	T_{IOTCK}/T_{IOCKT}	0.34 / 0	0.7 / 0	0.8 / 0	0.9 / 0	ns, min
3-State Setup Times, TCE input	$T_{IOTCECK}/T_{IOCKTCE}$	0.41 / 0	0.9 / 0	0.9 / 0	1.1 / 0	ns, min
3-State Setup Times, SR input (TFF)	$T_{IOSRCKT}/T_{IOCKTSR}$	0.49 / 0	1.0 / 0	1.1 / 0	1.3 / 0	ns, min
Set/Reset Delays						
SR input to Pad (asynchronous)	T_{IOSRP}	1.6	3.8	4.1	4.6	ns, max
SR input to Pad high-impedance (asynchronous)(1)	T_{IOSRHZ}	1.6	3.1	3.4	3.9	ns, max
SR input to valid data on Pad (asynchronous)	T_{IOSRON}	2.0	4.2	4.6	5.1	ns, max
GSR to Pad	T_{IOGSRQ}	4.9	9.7	10.9	12.5	ns, max

Notes:

1. 3-state turn-off delays should not be adjusted.
2. A Zero "0" Hold Time listing indicates no hold time or a negative hold time. Negative values can not be guaranteed "best-case", but if a "0" is listed, there is no positive hold time.

IOB Output Switching Characteristics Standard Adjustments

Output delays terminating at a pad are specified for LVTTL with 12 mA drive and fast slew rate. For other standards, adjust the delays by the values shown.

Description	Symbol	Standard(1)	Speed Grade				Units
			Min	-6	-5	-4	
Output Delay Adjustments							
Standard-specific adjustments for output delays terminating at pads (based on standard capacitive load, Csl)	T_{OLVTTL_S2}	LVTTL, Slow, 2 mA	4.2	14.7	15.8	17.0	ns
	T_{OLVTTL_S4}	4 mA	2.5	7.5	8.0	8.6	ns
	T_{OLVTTL_S6}	6 mA	1.8	4.8	5.1	5.6	ns
	T_{OLVTTL_S8}	8 mA	1.2	3.0	3.3	3.5	ns
	T_{OLVTTL_S12}	12 mA	1.0	1.9	2.1	2.2	ns
	T_{OLVTTL_S16}	16 mA	0.9	1.7	1.9	2.0	ns
	T_{OLVTTL_S24}	24 mA	0.8	1.3	1.4	1.6	ns
	T_{OLVTTL_F2}	LVTTL, Fast, 2mA	1.9	13.1	14.0	15.1	ns
	T_{OLVTTL_F4}	4 mA	0.7	5.3	5.7	6.1	ns
	T_{OLVTTL_F6}	6 mA	0.2	3.1	3.3	3.6	ns
	T_{OLVTTL_F8}	8 mA	0.1	1.0	1.1	1.2	ns
	T_{OLVTTL_F12}	12 mA	0	0	0	0	ns
	T_{OLVTTL_F16}	16 mA	–0.10	–0.05	–0.05	–0.05	ns
	T_{OLVTTL_F24}	24 mA	–0.10	–0.20	–0.21	–0.23	ns
	$T_{OLVCMOS2}$	LVCMOS2	0.10	0.10	0.11	0.12	ns
	T_{OPCI33_3}	PCI, 33 MHz, 3.3 V	0.50	2.3	2.5	2.7	ns
	T_{OPCI33_5}	PCI, 33 MHz, 5.0 V	0.40	2.8	3.0	3.3	ns
	T_{OPCI66_3}	PCI, 66 MHz, 3.3 V	0.10	–0.40	–0.42	–0.46	ns
	T_{OGTL}	GTL	0.6	0.50	0.54	0.6	ns
	T_{OGTLP}	GTL+	0.7	0.8	0.9	1.0	ns
	T_{OHSTL_I}	HSTL I	0.10	–0.50	–0.53	–0.5	ns
	T_{OHSTL_III}	HSTL III	–0.10	–0.9	–0.9	–1.0	ns
	T_{OHSTL_IV}	HSTL IV	–0.20	–1.0	–1.0	–1.1	ns
	T_{OSSTL2_I}	SSTL2 I	–0.10	–0.50	–0.53	–0.5	ns
	T_{OSSLT2_II}	SSTL2 II	–0.20	–0.9	–0.9	–1.0	ns
	T_{OSSTL3_I}	SSTL3 I	–0.20	–0.50	–0.53	–0.5	ns
	T_{OSSTL3_II}	SSTL3 II	–0.30	–1.0	–1.0	–1.1	ns
	T_{OCTT}	CTT	0	–0.6	–0.6	–0.6	ns
	T_{OAGP}	AGP	0	–0.9	–0.9	–1.0	ns

Notes:

1. Output timing is measured at 1.4 V with 35 pF external capacitive load for LVTTL. For other I/O standards and different loads, see Table 2 and Table 3.

I/O Standard Global Clock Input Adjustments

Description	Symbol	Standard(1)	Speed Grade				Units
			Min	-6	-5	-4	
Data Input Delay Adjustments							
Standard-specific global clock input delay adjustments	$T_{GPLVTTL}$	LVTTL	0	0	0	0	ns, max
	$T_{GPLVCMOS2}$	LVCMOS2	–0.02	–0.04	–0.04	–0.05	ns, max
	$T_{GPPCI33\_3}$	PCI, 33 MHz, 3.3 V	–0.05	–0.11	–0.12	–0.14	ns, max
	$T_{GPPCI33\_5}$	PCI, 33 MHz, 5.0 V	0.13	0.25	0.28	0.33	ns, max
	$T_{GPPCI66\_3}$	PCI, 66 MHz, 3.3 V	–0.05	–0.11	–0.12	–0.14	ns, max
	T_{GPGTL}	GTL	0.7	0.8	0.9	0.9	ns, max
	T_{GPGTLP}	GTL+	0.7	0.8	0.8	0.8	ns, max
	T_{GPHSTL}	HSTL	0.7	0.7	0.7	0.7	ns, max
	$T_{GPSSTL2}$	SSTL2	0.6	0.52	0.51	0.50	ns, max
	$T_{GPSSTL3}$	SSTL3	0.6	0.6	0.55	0.54	ns, max
	T_{GPCTT}	CTT	0.7	0.7	0.7	0.7	ns, max
	T_{GPAGP}	AGP	0.6	0.54	0.53	0.52	ns, max

Notes:

1. Input timing for GPLVTTL is measured at 1.4 V. For other I/O standards, see Table 3.

CLB Switching Characteristics

Delays originating at F/G inputs vary slightly according to the input used. The values listed below are worst-case. Precise values are provided by the timing analyzer.

Description	Symbol	Speed Grade				Units
		Min	-6	-5	-4	
Combinatorial Delays						
4-input function: F/G inputs to X/Y outputs	T_{ILO}	0.29	0.6	0.7	0.8	ns, max
5-input function: F/G inputs to F5 output	T_{IF5}	0.32	0.7	0.8	0.9	ns, max
5-input function: F/G inputs to X output	T_{IF5X}	0.36	0.8	0.8	1.0	ns, max
6-input function: F/G inputs to Y output via F6 MUX	T_{IF6Y}	0.44	0.9	1.0	1.2	ns, max
6-input function: F5IN input to Y output	T_{F5INY}	0.17	0.32	0.36	0.42	ns, max
Incremental delay routing through transparent latch to XQ/YQ outputs	T_{IFNCTL}	0.31	0.7	0.7	0.8	ns, max
BY input to YB output	T_{BYYB}	0.27	0.53	0.6	0.7	ns, max
Sequential Delays						
FF Clock CLK to XQ/YQ outputs	T_{CKO}	0.54	1.1	1.2	1.4	ns, max
Latch Clock CLK to XQ/YQ outputs	T_{CKLO}	0.6	1.2	1.4	1.6	ns, max
Setup and Hold Times before/after Clock CLK(1)		Setup Time / Hold Time				
4-input function: F/G Inputs	T_{ICK}/T_{CKI}	0.6 / 0	1.2 / 0	1.4 / 0	1.5 / 0	ns, min
5-input function: F/G inputs	T_{IF5CK}/T_{CKIF5}	0.7 / 0	1.3 / 0	1.5 / 0	1.7 / 0	ns, min
6-input function: F5IN input	T_{F5INCK}/T_{CKF5IN}	0.46 / 0	1.0 / 0	1.1 / 0	1.2 / 0	ns, min
6-input function: F/G inputs via F6 MUX	T_{IF6CK}/T_{CKIF6}	0.8 / 0	1.5 / 0	1.7 / 0	1.9 / 0	ns, min
BX/BY inputs	T_{DICK}/T_{CKDI}	0.30 / 0	0.6 / 0	0.7 / 0	0.8 / 0	ns, min
CE input	T_{CECK}/T_{CKCE}	0.37 / 0	0.8 / 0	0.9 / 0	1.0 / 0	ns, min
SR/BY inputs (synchronous)	$T_{RCK}T_{CKR}$	0.33 / 0	0.7 / 0	0.8 / 0	0.9 / 0	ns, min
Clock CLK						
Minimum Pulse Width, High	T_{CH}	0.8	1.5	1.7	2.0	ns, min
Minimum Pulse Width, Low	T_{CL}	0.8	1.5	1.7	2.0	ns, min
Set/Reset						
Minimum Pulse Width, SR/BY inputs	T_{RPW}	1.3	2.5	2.8	3.3	ns, min
Delay from SR/BY inputs to XQ/YQ outputs (asynchronous)	T_{RQ}	0.54	1.1	1.3	1.4	ns, max
Delay from GSR to XQ/YQ outputs	T_{IOGSRQ}	4.9	9.7	10.9	12.5	ns, max
Toggle Frequency (MHz) (for export control)	F_{TOG} (MHz)	625	333	294	250	MHz

Notes:

1. A Zero "0" Hold Time listing indicates no hold time or a negative hold time. Negative values cannot be guaranteed "best-case", but if a "0" is listed, there is no positive hold time.

Block RAM Switching Characteristics

Description	Symbol	Speed Grade				Units
		Min	-6	-5	-4	
Sequential Delays						
Clock CLK to DOUT output	T_{BCKO}	1.7	3.4	3.8	4.3	ns, max
Setup and Hold Times before/after Clock CLK(1)	Setup Time / Hold Time					
ADDR inputs	T_{BACK}/T_{BCKA}	0.6 / 0	1.2 / 0	1.3 / 0	1.5 / 0	ns, min
DIN inputs	T_{BDCK}/T_{BCKD}	0.6 / 0	1.2 / 0	1.3 / 0	1.5 / 0	ns, min
EN input	T_{BECK}/T_{BCKE}	1.3 / 0	2.6 / 0	3.0 / 0	3.4 / 0	ns, min
RST input	T_{BRCK}/T_{BCKR}	1.3 / 0	2.5 / 0	2.7 / 0	3.2 / 0	ns, min
WEN input	T_{BWCK}/T_{BCKW}	1.2 / 0	2.3 / 0	2.6 / 0	3.0 / 0	ns, min
Clock CLK						
Minimum Pulse Width, High	T_{BPWH}	0.8	1.5	1.7	2.0	ns, min
Minimum Pulse Width, Low	T_{BPWL}	0.8	1.5	1.7	2.0	ns, min
CLKA -> CLKB setup time for different ports	T_{BCCS}		3.0	3.5	4.0	ns, min

Notes:

1. A Zero "0" Hold Time listing indicates no hold time or a negative hold time. Negative values can not be guaranteed "best-case", but if a "0" is listed, there is no positive hold time.

TBUF Switching Characteristics

Description	Symbol	Speed Grade				Units
		Min	-6	-5	-4	
Combinatorial Delays						
IN input to OUT output	T_{IO}	0	0	0	0	ns, max
TRI input to OUT output high-impedance	T_{OFF}	0.05	0.09	0.10	0.11	ns, max
TRI input to valid data on OUT output	T_{ON}	0.05	0.09	0.10	0.11	ns, max

JTAG Test Access Port Switching Characteristics

Description	Symbol	Speed Grade			Units
		-6	-5	-4	
TMS and TDI Setup times before TCK	T_{TAPTCK}	4.0	4.0	4.0	ns, min
TMS and TDI Hold times after TCK	T_{TCKTAP}	2.0	2.0	2.0	ns, min
Output delay from clock TCK to output TDO	T_{TCKTDO}	11.0	11.0	11.0	ns, max
Maximum TCK clock frequency	F_{TCK}	33	33	33	MHz, max

DLL Timing Parameters

All devices are 100 percent functionally tested. Because of the difficulty in directly measuring many internal timing parameters, those parameters are derived from benchmark timing patterns. The following guidelines reflect worst-case values across the recommended operating conditions.

Description	Symbol	Speed Grade						Units
		-6		-5		-4		
		Min	Max	Min	Max	Min	Max	
Input Clock Frequency (CLKDLLHF)	FCLKINHF	60	200	60	180	60	180	MHz
Input Clock Frequency (CLKDLL)	FCLKINLF	25	100	25	90	25	90	MHz
Input Clock Pulse Width (CLKDLLHF)	$T_{DLLPWHF}$	2.0	-	2.4	-	2.4	-	ns
Input Clock Pulse Width (CLKDLL)	$T_{DLLPWLF}$	2.5	-	3.0		3.0	-	ns

Notes:

1. All specifications correspond to Commercial Operating Temperatures (0°C to + 85°C).

DLL Clock Tolerance, Jitter, and Phase Information

All DLL output jitter and phase specifications determined through statistical measurement at the package pins using a clock mirror configuration and matched drivers.

Description	Symbol	F_{CLKIN}	CLKDLLHF		CLKDLL		Units
			Min	Max	Min	Max	
Input Clock Period Tolerance	T_{IPTOL}		-	1.0	-	1.0	ns
Input Clock Jitter Tolerance (Cycle to Cycle)	T_{IJITCC}		-	± 150	-	± 300	ps
Time Required for DLL to Acquire Lock	T_{LOCK}	> 60 MHz	-	20	-	20	µs
		50 - 60 MHz	-	-	-	25	µs
		40 - 50 MHz	-	-	-	50	µs
		30 - 40 MHz	-	-	-	90	µs
		25 - 30 MHz	-	-	-	120	µs
Output Jitter (cycle-to-cycle) for any DLL Clock Output (1)	T_{OJITCC}			± 60		± 60	ps
Phase Offset between CLKIN and CLKO (2)	T_{PHIO}			± 100		± 100	ps
Phase Offset between Clock Outputs on the DLL (3)	T_{PHOO}			± 140		± 140	ps
Maximum Phase Difference between CLKIN and CLKO (4)	T_{PHIOM}			± 160		± 160	ps
Maximum Phase Difference between Clock Outputs on the DLL (5)	T_{PHOOM}			± 200		± 200	ps

Notes:

1. **Output Jitter** is cycle-to-cycle jitter measured on the DLL output clock, *excluding* input clock jitter.
2. **Phase Offset between CLKIN and CLKO** is the worst-case fixed time difference between rising edges of CLKIN and CLKO, *excluding* Output Jitter and input clock jitter.
3. **Phase Offset between Clock Outputs on the DLL** is the worst-case fixed time difference between rising edges of any two DLL outputs, *excluding* Output Jitter and input clock jitter.
4. **Maximum Phase Difference between CLKIN an CLKO** is the sum of Output Jitter and Phase Offset between CLKIN and CLKO, or the greatest difference between CLKIN and CLKO rising edges due to DLL alone (*excluding* input clock jitter).
5. **Maximum Phase DIfference between Clock Outputs on the DLL** is the sum of Output JItter and Phase Offset between any DLL clock outputs, or the greatest difference between any two DLL output rising edges sue to DLL alone (*excluding* input clock jitter).
6. All specifications correspond to Commercial Operating Temperatures (0°C to +85°C).

Table 2: **Virtex Pinout Tables (Chip-Scale and QFP Packages)** ***(Continued)***

Pin Name	Device	CS144	TQ144	PQ/HQ240
V_{CCO}	All	Banks 0 and 1: A2, A13, D7 Banks 2 and 3: B12, G11, M13 Banks 4 and 5: N1, N7, N13 Banks 6 and 7: B2, G2, M2	No I/O Banks in this package: 1, 17, 37, 55, 73, 92, 109, 128	No I/O Banks in this package: 15, 30, 44, 61, 76, 90, 105, 121, 136, 150, 165, 180, 197, 212, 226, 240
V_{REF}, Bank 0 (V_{REF} pins are listed incrementally. Connect all pins listed for both the required device and all smaller devices listed in the same package.) Within each bank, if input reference voltage is not required, all V_{REF} pins are general I/O.	XCV50	C4, D6	5, 13	218, 232
	XCV100/150	... + B4	... + 7	... + 229
	XCV200/300	N/A	N/A	... + 236
	XCV400	N/A	N/A	... + 215
	XCV600	N/A	N/A	... + 230
	XCV800	N/A	N/A	... + 222
V_{REF}, Bank 1 (V_{REF} pins are listed incrementally. Connect all pins listed for both the required device and all smaller devices listed in the same package.) Within each bank, if input reference voltage is not required, all V_{REF} pins are general I/O.	XCV50	A10, B8	22, 30	191, 205
	XCV100/150	... + D9	... + 28	... + 194
	XCV200/300	N/A	N/A	... + 187
	XCV400	N/A	N/A	... + 208
	XCV600	N/A	N/A	... + 193
	XCV800	N/A	N/A	... + 201
V_{REF}, Bank 2 (V_{REF} pins are listed incrementally. Connect all pins listed for both the required device and all smaller devices listed in the same package.) Within each bank, if input reference voltage is not required, all V_{REF} pins are general I/O.	XCV50	D11, F10	42, 50	157, 171
	XCV100/150	... + D13	... + 44	... + 168
	XCV200/300	N/A	N/A	... + 175
	XCV400	N/A	N/A	... + 154
	XCV600	N/A	N/A	... + 169
	XCV800	N/A	N/A	... + 161

Table 3: **Virtex Pinout Tables (BGA) *(Continued)***

Pin Name	Device	BG256	BG352	BG432	BG560
V_{CCO}, Bank 7	All	G4, H4	G23, K26, N23	A31, L28, L31	C32, D33, K33, N32, T33
V_{REF}, Bank 0 (VREF pins are listed incrementally. Connect all pins listed for both the required device and all smaller devices listed in the same package.) Within each bank, if input reference voltage is not required, all V_{REF} pins are general I/O.	XCV50	A8, B4	N/A	N/A	N/A
	XCV100/150	... + A4	A16,C19, C21	N/A	N/A
	XCV200/300	... + A2	... + D21	B19, D22, D24, D26	N/A
	XCV400	N/A	N/A	... + C18	A19, D20, D26, E23, E27
	XCV600	N/A	N/A	... + C24	... + E24
	XCV800	N/A	N/A	... + B21	... + E21
	XCV1000	N/A	N/A	N/A	... + D29
V_{REF}, Bank 1 (VREF pins are listed incrementally. Connect all pins listed for both the required device and all smaller devices listed in the same package.) Within each bank, if input reference voltage is not required, all V_{REF} pins are general I/O.	XCV50	A17, B12	N/A	N/A	N/A
	XCV100/150	... + B15	B6, C9, C12	N/A	N/A
	XCV200/300	... + B17	... + D6	A13, B7, C6, C10	N/A
	XCV400	N/A	N/A	... + B15	A6, D7, D11, D16, E15
	XCV600	N/A	N/A	... + D10	... + D10
	XCV800	N/A	N/A	... + B12	... + D13
	XCV1000	N/A	N/A	N/A	... + E7
V_{REF}, Bank 2 (V_{REF} pins are listed incrementally. Connect all pins listed for both the required device and all smaller devices listed in the same package.) Within each bank, if input reference voltage is not required, all V_{REF} pins are general I/O.	XCV50	C20, J18	N/A	N/A	N/A
	XCV100/150	... + F19	E2, H2, M4	N/A	N/A
	XCV200/300	... + G18	... + D2	E2, G3, J2, N1	N/A
	XCV400	N/A	N/A	... + R3	G5, H4, L5, P4, R1
	XCV600	N/A	N/A	... + H1	... + K5
	XCV800	N/A	N/A	... + M3	... + N5
	XCV1000	N/A	N/A	N/A	... + B3

BG432 Pin Function Diagram

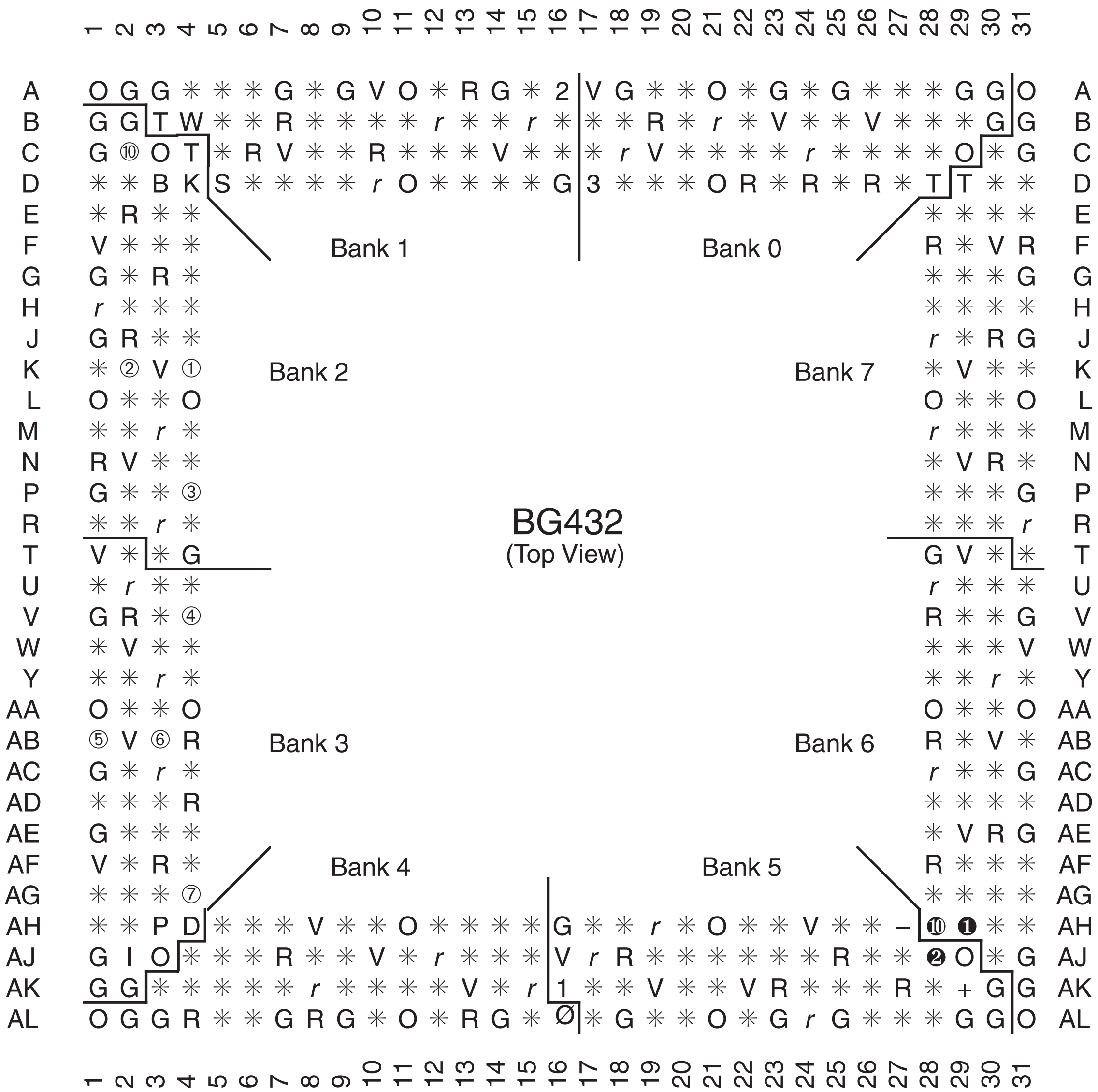

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Figure 6: **BG432 Pin Function Diagram**

FG676 Pin Function Diagram

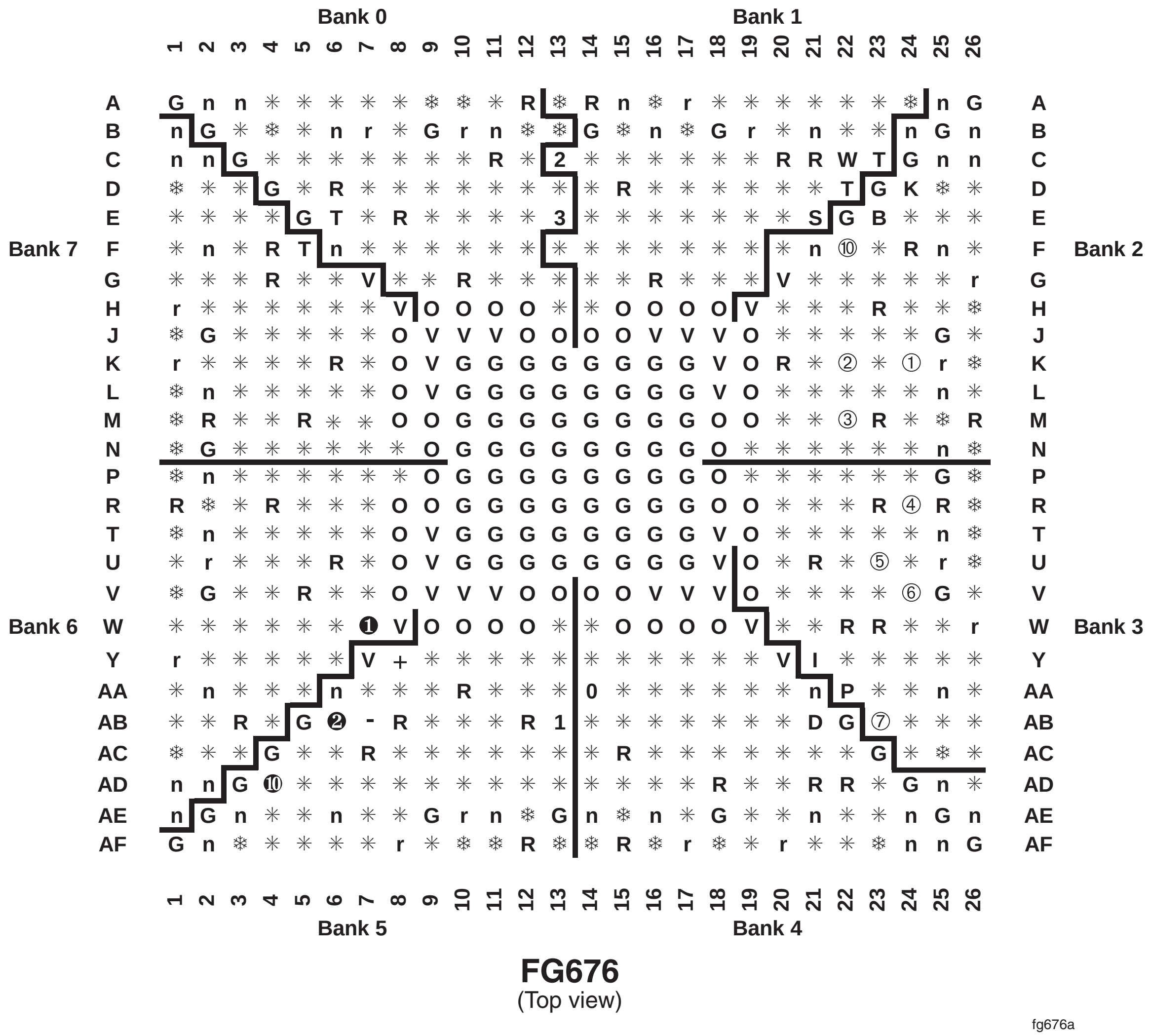

Figure 10: **FG676 Pin Function Diagram**

Notes:

Packages FG456 and FG676 are layout compatible.

Revision History

Date	Version	Revision
11/98	1.0	Initial Xilinx release.
01/99-02/99	1.2-1.3	Both versions updated package drawings and specs.
05/99	1.4	Addition of package drawings and specifications.
05/99	1.5	Replaced FG 676 & FG680 package drawings.
07/99	1.6	Changed Boundary Scan Information and changed Figure 11, Boundary Scan Bit Sequence. Updated IOB Input & Output delays. Added Capacitance info for different I/O Standards. Added 5 V tolerant information. Added DLL Parameters and waveforms and new Pin-to-pin Input and Output Parameter tables for Global Clock Input to Output and Setup and Hold. Changed Configuration Information including Figures 12, 14, 17 & 19. Added device-dependent listings for quiescent currents ICCINTQ and ICCOQ. Updated IOB Input and Output Delays based on default standard of LVTTL, 12 mA, Fast Slew Rate. Added IOB Input Switching Characteristics Standard Adjustments.
09/99	1.7	Speed grade update to preliminary status, Power-on specification and Clock-to-Out Minimums additions, "0" hold time listing explanation, quiescent current listing update, and Figure 6 ADDRA input label correction. Added T_{IJITCC} parameter, changed T_{OJIT} to T_{OPHASE}.
01/00	1.8	Update to speed.txt file 1.96. Corrections for CRs 111036,111137, 112697, 115479, 117153, 117154, and 117612. Modified notes for Recommended Operating Conditions (voltage and temperature). Changed Bank information for V_{CCO} in CS144 package on p.43.
01/00	1.9	Updated DLL Jitter Parameter table and waveforms, added Delay Measurement Methodology table for different I/O standards, changed buffered Hex line info and Input/Output Timing measurement notes.
03/00	2.0	New TBCKO values; corrected FG680 package connection drawing; new note about status of CCLK pin after configuration.
05/00	2.1	Modified "Pins not listed..." statement. Speed grade update to Final status.
05/00	2.2	Modified Table 18.
09/00	2.3	• Added XCV400 values to table under **Minimum Clock-to-Out for Virtex Devices**. • Corrected Units column in table under **IOB Input Switching Characteristics**. • Added values to table under **CLB SelectRAM Switching Characteristics**.
10/00	2.4	• Corrected pinout info for devices in the BG256, BG432, and BG560 pkgs in Table 18. • Corrected **BG256 Pin Function Diagram**.
04/02/01	2.5	• Revised minimums for **Global Clock Set-Up and Hold for LVTTL Standard, with DLL**. • Converted file to modularized format. See section **Virtex Data Sheet**, below.
04/19/01	2.6	• Corrected pinout information for FG676 device in Table 4. (Added AB22 pin.)
07/19/01	2.7	• Clarified V_{CCINT} pinout information and added AE19 pin for BG352 devices in Table 3. • Changed pinouts listed for BG352 XCV400 devices in banks 0 thru 7.
07/19/02	2.8	• Changed pinouts listed for GND in TQ144 devices (see Table 2).
03/01/13	4.0	The products listed in this data sheet are obsolete. See XCN10016 for further information.

Virtex Data Sheet

The Virtex Data Sheet contains the following modules:

- DS003-1, Virtex 2.5V FPGAs:
  Introduction and Ordering Information (Module 1)
- DS003-2, Virtex 2.5V FPGAs:
  Functional Description (Module 2)
- DS003-3, Virtex 2.5V FPGAs:
  DC and Switching Characteristics (Module 3)
- DS003-4, Virtex 2.5V FPGAs:
  Pinout Tables (Module 4)